



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Abdullahman Sezginer et al.

Application No.: 10/613,378

Filed: July 3, 2003

For: OVERLAY METROLOGY METHOD
AND APPARATUS USING MORE
THAN ONE GRATING PER
MEASUREMENT DIRECTION

Confirmation No.: 7200

Group Art Unit: 2877

Examiner: Gordon J. Stock, Jr.

**RESPONSE TO OFFICE ACTION
MAILED APRIL 19, 2006**

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San Francisco, CA 94111
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M/S AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
with the United States Postal Service as First Class Mail in an
envelope, addressed to: Commissioner for Patents, P.O.
Box 1450, Alexandria, VA 22313-1450 on June 21, 2006.

STALLMAN & POLLOCK LLP

Dated: 06/21/2006

By:

Georgia K. Stith

Sir:

In response to the Office Action dated April 19, 2005, please amend the above-identified
application as follows:

Amendment to the Claims are reflected in the listing of claims which begins on page 2 of this
paper.

Remarks begin on page 4 of this paper.